

Form PTO 1449  U.S. Department of Commerce Patent and Trademark Office  Information Disclosure Statement by Applicant	ATTY. DOCKET NUMBER	SERIAL NUMBER
	NITT.0142	To be Assigned
	APPLICANT	
	HATANO et al.	
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**U.S. Patent Documents**

Examiner Initial	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

**Foreign Patent Documents**

Examiner Initial	DOCUMENT NUMBER	FILING DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
						YES	NO
S.M.	2002-43222	2/21/95	Japan			Abstract	X
S.M.	2002-100637	2/21/95	Japan			Abstract	X

**Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)**

S.M.	C.T. Angelis, C.A. Dimitriadis, M. Miyasaka, F.V. Farmakis, G. Kamarinos, J. Brini and J. Stoemenos, "Effect of Excimer Laser Annealing on the Structural and Electrical Properties of Polycrystalline Silicon Thin-Film Transistors", Journal of Applied Physics (15 October 1999), Vol. 86, No. 8, pp. 4600-4606
S.M.	Hiroyuki Kuriyama, Tomoyuki, Nohda, Satoshi Ishida, Takashi Kuwahara, Shigeru Noguchi, Seiichi Kiyama, Shinya Tsuda and Shoichi Nakano, "Lateral Grain Growth of Poly-Si Films with a Specific Orientation by an Excimer Laser Annealing Method", Jpn. J. Appl. Phys., Vol. 32 (1993), pp. 6190-6195
S.M.	Kenkichi Suzuki, Masakazu Saitou, Michiko Takahashi, Nobuaki Hayashi and Takao Terabayashi, "Correlation Between Power Density Fluctuation and Grain Size Distribution of Laser Annealed Polycrystalline Silicon", Part of the SPIE Conference on Laser Applications in Microelectronics and Optoelectronic Manufacturing IV, January 1999, SPIE Vol. 3618, pp. 310-319
EXAMINER	DATE CONSIDERED
/Seokyun Moon/	06/12/2006
EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant	